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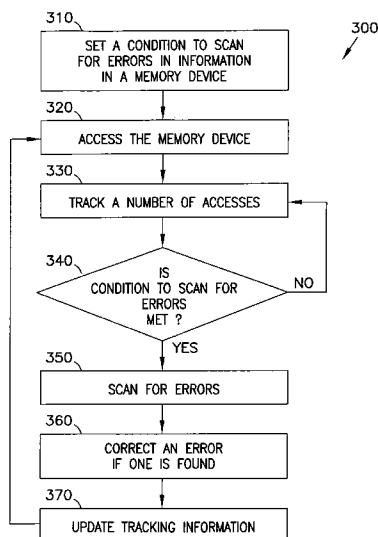


FIG. 3

(57) Abstract: Various embodiments include methods, apparatus, and systems to scan at least a portion of a memory device when a condition for scanning is met. The condition may be dependent on one or more of a number of read operations, a number of write operations, time, and others. Other embodiments including additional methods, apparatus, and systems are disclosed.

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